# MSKSEMI 美森科













**ESD** 

1/5

TSS

MOV

GDT

PLED

## MSESD223F24PU

**Product specification** 





#### **Features**

- 3-pin lead-less package
- Junction capacitance (Max value: 850pF)
- Peak Pulse Current (8/20µs) MAX: 150A
- IEC61000-4-2 (ESD) ±30kV (air), ±30kV (contact)
- Low clamping voltage
- Low leakage current
- Working voltages: 24V
- RoHS Compliant

#### **Mechanical Characteristics**

Package: DFN2020-3L

Lead Finish:Matte Tin

Case Material: "Green" Molding Compound.

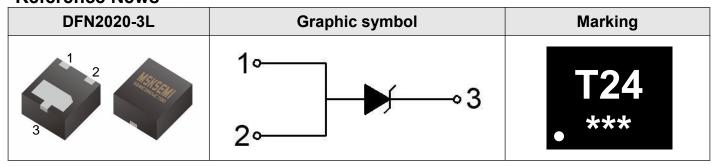
UL Flammability Classification Rating 94V-0

• Moisture Sensitivity: Level 3 per J-STD-020

#### **Applications**

- Power Management
- Industrial Application
- Power Supply Protection

#### **Reference News**





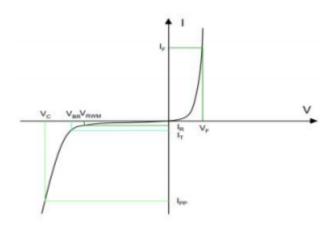
## Absolute Maximum Ratings (T=25°C, RH=45%-75%, unless otherwise noted)

Parameters	Symbol	Value	Unit
Peak Pulse Power (tp=8/20µs waveform)	P <sub>PP</sub>	7500	W
Peak Pulse Current (8/20μs)	<b>I</b> PP	150	А
ESD per IEC 61000-4-2 (Air) ESD per IEC 61000-4-2 (Contact)	V <sub>ESD</sub>	±30 ±30	KV
Operating Temperature Range	TJ	−55 to +125	°C
Storage Temperature Range	Tstg	-55 to +150	°C

## Electrical Characteristics (T=25°C, RH=45%-75%, unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Reverse Working Voltage	VRWM				24	V
Reverse Breakdown Voltage	$V_{\mathtt{BR}}$	k = 1mA	24.8		29.5	V
Reverse Leakage Current	<b>I</b> R	V <sub>R</sub> = 24V			1	uA
Clamping voltage	Vc	I <sub>PP</sub> = 50A,T <sub>P</sub> =8/20us			32	V
Clamping voltage	Vc	I <sub>PP</sub> = 150A,T <sub>P</sub> =8/20us			40	V
Junction capacitance	CJ	V <sub>R</sub> =0V,f =1MHz			850	pF

Symbol	Parameter	
VRWM	Peak Reverse Working Voltage	
lR	Reverse Leakage Current @VRWM	
VBR	Breakdown Voltage @Iт	
ΙΤ	Test Current	
IPP	Maximum Reverse Peak Pulse Current	
Vc	Clamping Voltage @IPP	
PPP	Peak Pulse Power	
Сл	Junction Capacitance	
lF	Forward Current	
VF	Forward Voltage @IF	





## **TypicalCharacteristics**

FIG1: Power rating derating curve

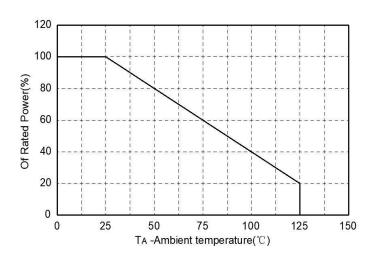


FIG2: pulse Waveform

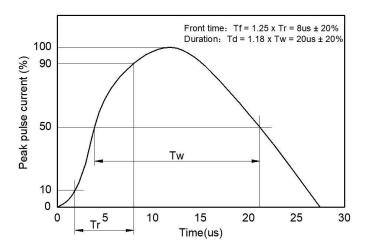


FIG3: Capacitance between teminals charateristics

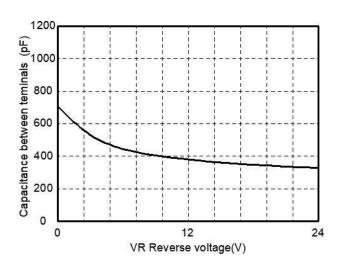
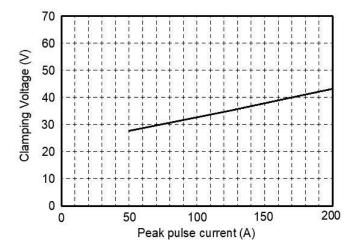


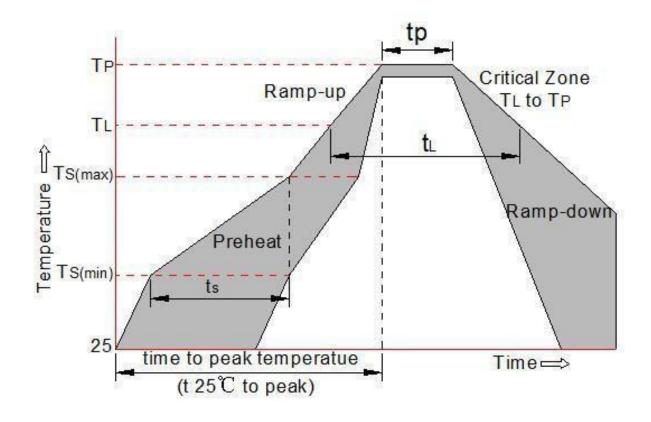
FIG4: Clamping Voltage vs. Peak Pulse Current





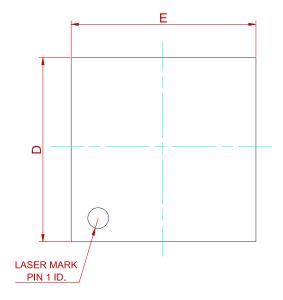
## **Soldering Parameters**

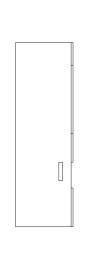
	Reflow Condition	Pb-Free assembly (see as bellow)	
	-Temperature Min (T <sub>s(min)</sub> )	+150℃	
Pre Heat	-Temperature Max(T <sub>s(max)</sub> )	+200℃	
	-Time (Min to Max) (ts)	60-180 secs.	
Averag	e ramp up rate (Liquid us Temp (Tւ) to peak)	3℃/sec. Max	
	$T_{s(max)}$ to $T_L$ - Ramp-up Rate	3℃/sec. Max	
D-9	-Temperature(T <sub>∟</sub> ) (Liquid us)	+217℃	
Reflow	-Temperature(t₋)	60-150 secs.	
	Peak Temp (T <sub>p</sub> )	<b>+260(+0/-5)</b> ℃	
	Time within 5℃of actual Peak Temp (t٫)	30 secs. Max	
	Ramp-down Rate	6℃/sec. Max	
	Time 25℃to Peak Temp (T <sub>P</sub> )	8 min. Max	
	Do not exceed	+260℃	

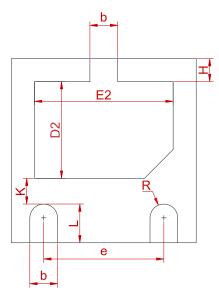




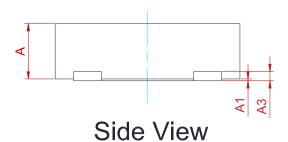
#### **PACKAGEMECHANICALDATA**







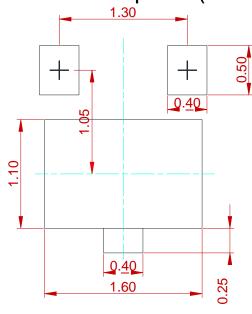
Top View



**Bottom View** 

Cumbal	Dimensions In Millimeters			
Symbol	Min.	Тур.	Max.	
Α	0.50	0.58	0.60	
A1	0.00	0.02	0.05	
А3	0.10 REF.			
b	0.25	0.30	0.35	
D	1.90	2.00	2.10	
Е	1.90	2.00	2.10	
D2	0.95	1.05	1.15	
E2	1.40	1.50	1.60	
е	1.20	1.30	1.40	
Н	0.20	0.25	0.30	
K	0.20	0.30	0.40	
Ĺ	0.33	0.39	0.45	

## Recommended land pattern (Unit: mm)



#### Notes:

R

This recommended land pattern is for reference purposes only. Please consult your manufacturing group to ensure your PCB design guidelines are met.

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## **REELSPECIFICATION**

P/N	PKG	QTY
MSESD223F24PU	DFN2020-3L	3000



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